



## DOCUMENT CHANGE REQUEST

DCR number 1156 Changes required for: General

Date: 2018/10/29

Date sent: 2018/04/09

Status: IMPLEMENTED

Originator: Steve Thacker

Organisation: ESCC Executive  
Secretariat

Title: Transistors, Microwave, Small Signal, Silicon, Bipolar, based on Type BFY740B

Number: 5611/011

Issue: 3

Other documents affected:

Page:

See attachment 5611/011 Draft 4B

Paragraph:

See below and in attachment 5611/011 Draft 4B

Original wording:

See 5611/011 issue 3

Proposed wording:

The following changes are proposed as detailed (highlighted yellow) in the attachment:  
ESCC5611011 Draft 4B in review.docx:

- A) Various minor editorial changes are implemented as highlighted in the attachment.
- B) Para 1.4.2: add new Variant 02 with different die metallisation compared to Variant 01 (Die Metallisation column is also added to table)
- C) Para 2.1.1: Add new deviation on Radiographic Inspection during Screening Tests.
- D) Para 2.5.1 Characteristic ICEX: new limits are added for new Variant 02.

Justification:

The technical changes included above (points B C D) are as proposed by ESCC Qualified Manufacturer Infineon.

Attachments:

esc5611011\_draft\_4b\_in\_review.docx

Modifications:

N/A

Approval signature:

A handwritten signature in black ink, appearing to read "Stephen R. ...".

Date signed:

2018-10-29